[Broad Band Monitoring]

The precise production of coating systems with complicated designs has developed to one of the major challenges in modern optical thin film technology.

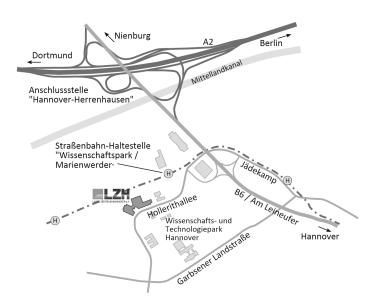
Besides extended investigations in the stability and reproducibility of deposition techniques, a variety of approaches to control the growing layers has been studied on the way towards the targeted ideal process concept which would allow the realization of even extremely complicated coating designs in a linear chain without iteration steps.

Even though this ultimate production technique could not be achieved completely until now, the related research work of the last two decades furnished enormous progresses, especially in the field of onlinemonitoring in deposition processes.

The present workshop is dedicated to a comprehensive overview on the latest achievements in the area of thin film monitoring.

[How to get there]

Laser Zentrum Hannover e.V. (LZH), Hollerithallee 8, 30419 Hannover



[Organizer]

PhotonicNet GmbH

Dr.-Ing. Thomas Fahlbusch Tel.: 0511 / 277-1640 fahlbusch@photonicnet.de

[in cooperation with]

Laser Zentrum Hannover e.V.

Prof. Dr. Detlev Ristau Tel.: 0511 / 2788-0 d.ristau@lzh.de

Photonic Net

Innovationsnetz Optische Technologien

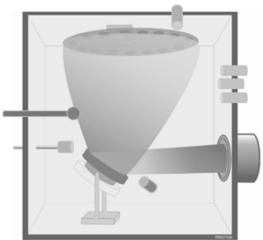
IN COOPERATION WITH





Monitoring in Thin Film Production

[Hanover, Germany February 20th, 2018]





Hanover February 20th, 2018

[Agenda]

Welcome 09.30 Detlev Ristau

Laser Zentrum Hannover e.V., Hanover, Germany

Session I: Fundamentals

Monitoring and Control of 09.40 Optical Deposition Processes

Henrik Ehlers

Laser Zentrum Hannover e.V., Hanover, Germany

Design and Optical Monitoring

10.10

Alexander Tikhonravov Lomonossow University, Moscow, Russia

Optical Monitoring in Modern 10.40 Deposition Processes

Detlef Arhilger

Bühler Group, Leybold Optics, Alzenau, Germany

Coffee break, photograph

11.10

Session II: Applications

Filter Systems 11.30

Marc Lappschies

Optic Balzers Jena GmbH, Jena, Germany

N.N. 12.00

Dirk Isfort, Carl Zeiss GmbH, Oberkochen, Germany

Optical Monitoring in IBS 12.30

Kai Starke

CEC Cutting Edge Coatings GmbH, Hanover, Germany

Lunch break

12.40

15.00

Session III: Applications

Chirped Mirrors 14.00

Vladimir Pervak

Ludwig-Maximilians-University, Munich, Germany

Prospects for the enhancement of PIAD processes by monitoring of optical thickness and plasma parameters

Jens Harhausen

Leibniz-Institute for Plasma Science and Technology, INP Greifswald. Germany

Coffee break

Session IV: Advanced Monitoring Concepts

Optical Monitoring: New Approaches 15.30

Sebastian Schlichting

Laser Zentrum Hannover e.V., Hanover, Germany

Automatic generation of 16.00 monochromatic monitoring spreadsheets

Tatiana Amotchkina,

Ludwig-Maximilians-University, Munich, Germany

Final remarks 16.30

Lab Tour LZH e.V. 16.40

End 18.00



[Registration]

Binding Registration

Please register until February 09th, 2018 the latest

Fax: +49 511 / 277-1650

or ONLINE

E-Mail: <u>veranstaltung@photonicnet.de</u>

☐ I will attend the workshop

Name

Company / Institution

Address

Postal Code, City

Phone No.

E-Mail

Member of competence network OT

Date / Signature

Venue:

Laser Zentrum Hannover e.V. Hollerithallee 8 30419 Hannover

Germany

PARTICIPATION FEE (plus VAT 19%):

290,00 € per person 230,00 € per person for Members of competence network OT